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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded -</u> <u>Microcontrollers</u>"

Details

Product Status	Obsolete
Core Processor	M8C
Core Size	8-Bit
Speed	24MHz
Connectivity	I²C, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	28
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 1x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-QFN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c24293-24lqxi

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Designing with PSoC Designer

The development process for the PSoC device differs from that of a traditional fixed-function microprocessor. The configurable analog and digital hardware blocks give the PSoC architecture a unique flexibility that pays dividends in managing specification change during development and lowering inventory costs. These configurable resources, called PSoC blocks, have the ability to implement a wide variety of user-selectable functions. The PSoC development process is:

- 10.Select user modules.
- 11.Configure user modules.
- 12.Organize and connect.
- 13.Generate, verify, and debug.

Select User Modules

PSoC Designer provides a library of prebuilt, pretested hardware peripheral components called "user modules". User modules make selecting and implementing peripheral devices, both analog and digital, simple.

Configure User Modules

Each user module that you select establishes the basic register settings that implement the selected function. They also provide parameters and properties that allow you to tailor their precise configuration to your particular application. For example, a PWM User Module configures one or more digital PSoC blocks, one for each eight bits of resolution. Using these parameters, you can establish the pulse width and duty cycle. Configure the parameters and properties to correspond to your chosen application. Enter values directly or by selecting values from drop-down menus. All of the user modules are documented in datasheets that may be viewed directly in PSoC Designer or on the Cypress website. These user module datasheets explain the internal operation of the user module and provide performance specifications. Each datasheet describes the use of each user module parameter, and other information that you may need to successfully implement your design.

Organize and Connect

Build signal chains at the chip level by interconnecting user modules to each other and the I/O pins. Perform the selection, configuration, and routing so that you have complete control over all on-chip resources.

Generate, Verify, and Debug

When you are ready to test the hardware configuration or move on to developing code for the project, perform the "Generate Configuration Files" step. This causes PSoC Designer to generate source code that automatically configures the device to your specification and provides the software for the system. The generated code provides APIs with high-level functions to control and respond to hardware events at run time, and interrupt service routines that you can adapt as needed.

A complete code development environment lets you to develop and customize your applications in C, assembly language, or both.

The last step in the development process takes place inside PSoC Designer's Debugger (accessed by clicking the Connect icon). PSoC Designer downloads the HEX image to the ICE where it runs at full-speed. PSoC Designer debugging capabilities rival those of systems costing many times more. In addition to traditional single-step, run-to-breakpoint, and watch-variable features, the debug interface provides a large trace buffer. It lets you to define complex breakpoint events that include monitoring address and data bus values, memory locations, and external signals.



Pinouts

16-pin QFN (13 GPIOs) [2]

Table 2.	Pin Definitions – CY8C24093	[3]
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Pin	Ту	pe	Namo	Description
No.	Digital	Analog	Name	Description
1	I/O	I	P2[5]	Crystal output (XOut)
2	I/O	I	P2[3]	Crystal input (XIn)
3	IOHR	I	P1[7]	I ² C SCL, SPI SS
4	IOHR	I	P1[5]	I ² C SDA, SPI MISO
5	IOHR	I	P1[3]	SPI CLK
6	IOHR	I	P1[1]	ISSP CLK ^[4] , I ² C SCL, SPI MOSI
7	Po	wer	V_{SS}	Ground connection
8	IOHR	I	P1[0]	ISSP DATA ^[4] , I ² C SDA, SPI CLK ^[5]
9	IOHR	I	P1[2]	
10	IOHR	I	P1[4]	Optional external clock (EXTCLK)
11	In	put	XRES	Active high external reset with internal pull-down
12	IOH	I	P0[4]	
13	Po	wer	V_{DD}	Supply voltage
14	IOH	I	P0[7]	
15	IOH	I	P0[3]	
16	IOH	I	P0[1]	



LEGEND A = Analog, I = Input, O = Output, OH = 5 mA High Output Drive, R = Regulated Output.

Notes

No center pad.
 13 GPIOs.

5. Alternate SPI clock.

A. On power-up, the SDA(P1[0]) drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to high impedance state. On reset, after XRES de-asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I²C bus. Use alternate pins if you encounter issues.



32-pin QFN (28 GPIOs) [6]

Table 3. Pin Definitions – CY8C24193^[7]

Pin	Ту	ре	Namo	Description
No.	Digital	Analog	Name	Description
1	IOH	I	P0[1]	
2	I/O	I	P2[7]	
3	I/O	I	P2[5]	Crystal output (XOut)
4	I/O	I	P2[3]	Crystal input (XIn)
5	I/O	I	P2[1]	
6	I/O	I	P3[3]	
7	I/O	I	P3[1]	
8	IOHR	I	P1[7]	I ² C SCL, SPI SS
9	IOHR	I	P1[5]	I ² C SDA, SPI MISO
10	IOHR	I	P1[3]	SPI CLK.
11	IOHR	I	P1[1]	ISSP CLK ^[8] , I ² C SCL, SPI MOSI.
12	Po	wer	V _{SS}	Ground connection.
13	IOHR	I	P1[0]	ISSP DATA ^[8] , I ² C SDA, SPI CLK ^[9]
14	IOHR	I	P1[2]	
15	IOHR	I	P1[4]	Optional external clock input (EXTCLK)
16	IOHR	I	P1[6]	
17	In	out	XRES	Active high external reset with internal pull-down
18	I/O	I	P3[0]	
19	I/O	I	P3[2]	
20	I/O	I	P2[0]	
21	I/O	I	P2[2]	
22	I/O	I	P2[4]	
23	I/O	I	P2[6]	
24	IOH	I	P0[0]	
25	IOH	I	P0[2]	
26	IOH	I	P0[4]	
27	IOH	I	P0[6]	
28	Po	wer	V _{DD}	Supply voltage
29	IOH	I	P0[7]	
30	IOH	I	P0[5]	
31	IOH	I	P0[3]	
32	Po	wer	V _{SS}	Ground connection
CP	Po	wer	V_{SS}	Center pad must be connected to ground

Figure 3. CY8C24193



LEGEND A = Analog, I = Input, O = Output, OH = 5 mA High Output Drive, R = Regulated Output.

Notes

6. 28 GPIOs.

The center pad (CP) on the QFN package must be connected to ground (V_{SS}) for best mechanical, thermal, and electrical performance. If not connected to ground, it must be electrically floated and not connected to any other signal.

8. On power-up, the SDA(P1[0]) drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to high impedance state. On reset, after XRES de-asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I2C bus. Use alternate pins if you encounter issues.

9. Alternate SPI clock.



48-pin QFN (34 GPIOs) [14]

Table 5. Pin Definitions – CY8C24393, CY8C24693 ^[15, 16]

Pin No.	Digital	Analog	Name	Description	Figure 5. CY8C24393, CY8C24693 Device					vice
1			NC	No connection], AI	, ∠ ∠ ∠ ∠	
2	I/O	I	P2[7]					PO[1 VSS PO[3	NC NC NC PO[4 PO[2 PO[2 PO[0	
3	I/O	1	P2[5]	Crystal output (XOut)					14 4 4 4 4 4 6 8 8 6 1 1 4 6 6 7 6 8 8 6 1	
4	I/O	1	P2[3]	Crystal input (XIn)			AI ,P2[7]	2	35	P2[4], AI
5	I/O	1	P2[1]			A	, XOut,P2[5]	3	34	P2[2], AI
6	I/O	I	P4[3]			, A	AI , XIN ,P2[3] AI ,P2[1]	■ 4 ■ 5	33 32	P2[0], AI P4[2], AI
7	I/O	1	P4[1]				AI ,P4[3]	— 6	QFN 31=	P4[0], AI
8	I/O	1	P3[7]				AI ,P4[1] AI ,P3[7]	7	(Top View) 30= 29=	Р3[6], АІ Р3[4], АІ
9	I/O	1	P3[5]				AI,P3[5]	9	28	P3[2], AI
10	I/O	I	P3[3]				AI,P3[3] AI P3[1]	■ 10 ■ 11	27 - 2 /-	Y3[0], AI XRES
11	I/O	I	P3[1]			AI,I2 C SCL,	SPI SS,P1[7]	∎ 12€ 7 5	16 119 119 119 119 119 119 119 119 119 1	P1[6], AI
12	IOHR	1	P1[7]	I ² C SCL, SPI SS			(
13	IOHR	I	P1[5]	I ² C SDA, SPI MISO				14,11	LK PI	
14			NC	No connection				s o, A	1 MOS SPI C A A XTCL	
15			NC	No connection				IM M	SPIC L, SF SDA, S	
16	IOHR	1	P1[3]	SPI CLK				S YO	I2C S	
17	IOHR	I	P1[1]	ISSP CLK ^[17] , I ² C SCL, SPI MOSI				12 C S	AT A ¹ ,	
18	Power		V _{SS}	Ground connection					SP D	
19			NC	No connection					AI, IS AI, IS	
20			NC	No connection						
21	Power		V _{DD}	Supply voltage	Pin No.	Digital	Analog	Name	Descripti	on
22	IOHR	I	P1[0]	ISSP DATA ^[17] , I ² C SDA, SPI CLK ^[18]	36			NC	No connection	
23	IOHR	I	P1[2]		37	IOH	1	P0[0]		
24	IOHR	I	P1[4]	Optional external clock input (EXTCLK)	38	IOH	I	P0[2]		
25	IOHR	I	P1[6]		39	IOH	1	P0[4]		
26	Input		XRES	Active high external reset with internal pull-down	40	IOH	I	P0[6]		
27	I/O	I	P3[0]		41	Power	•	V _{DD}	Supply voltage	
28	I/O	1	P3[2]		42			NC	No connection	
29	I/O	1	P3[4]		43			NC	No connection	
30	I/O	I	P3[6]		44	IOH	1	P0[7]		
31	I/O	I	P4[0]		45			NC	No connection	
32	I/O	I	P4[2]		46	IOH	I	P0[3]		
33	I/O	I	P2[0]		47	Power		V _{SS}	Ground connection	
34	I/O	I	P2[2]		48	IOH	1	P0[1]		
35	I/O	I	P2[4]		CP	Power		V _{SS}	Center pad must be co ground	onnected to
LEG	ENDA = A	Analog, I =	Input, O	= Output, NC = No Connection H = 5	mA Hi	igh Output	t Drive, R	= Regula	ted Output	

Notes

14.38 GPIOs.

14. 38 GPIOS.
15. This part is available in limited quantities for In-Circuit Debugging during prototype development. It is not available in production volumes.
16. The center pad (CP) on the QFN package must be connected to ground (V_{SS}) for best mechanical, thermal, and electrical performance. If not connected to ground, it must be electrically floated and not connected to any other signal.
17. On Power-up, the SDA(P1[0]) drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to high impedance state. On reset, after XRES de- asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. In both cases, a pull-up resistance on these lines combines with the pull-down resistance (5.6K ohm) and form a potential divider. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I2C bus. Use alternate pins if you encounter issues.

18. Alternate SPI clock.



48-pin QFN (OCD) (36 GPIOs) [23]

The 48-pin QFN part is for the CY8C240093 On-Chip Debug (OCD). Note that this part is only used for in-circuit debugging.

Pin No.	Digital	Analog	Name	Description			Figu	re 7. CY	8C240093
1 ^[26]			OCDOE	OCD mode direction pin			< 	· Þ Þ .	ノ], A DE 0], A 0], A 0], A
2	I/O	I	P2[7]					Pol SS 10	POI POI
3	I/O	I	P2[5]	Crystal output (XOut)				47 46 45	
4	I/O	I	P2[3]	Crystal input (XIn)					35 □ P2[4].Al
5	I/O	I	P2[1]			AI, X	Out, P2[5] = 3		34 ⊑ P2[2],AI
6	I/O		P4[3]			AI,	Xln , P2[3] 🗖 4		33 = P2[0],AI
7	I/O		P4[1]				AI, P2[1] = 5		32 = P4[2],Al
8	I/O		P3[7]				AI, $P4[3] = 6$		
9	I/O	I	P3[5]				AI, P3[7] = 8	,	29 – P3[4], Al
10	I/O	I	P3[3]				AI, P3[5] 🗖 9		28 = P3[2],AI
11	I/O		P3[1]				AI, P3[3] = 10	I	27 = P3[0], Al
12	IOHR		P1[7]	I ² C SCL, SPI SS	ALIZ		AI, P3[1] = 11 I SS P1[7] = 12	м 4 10 40	26 ARES $\sim \infty \propto \infty \sim \infty \propto \pm 25$ P1[6] Al
13	IOHR		P1[5]	I ² C SDA, SPI MISO	,,				
14 ^[26]			CCLK	OCD CPU clock output			1		[1]] D + D + D - D - [0]
15 ^[26]			HCLK	OCD high speed clock output					
16	IOHR	I	P1[3]	SPI CLK.			Ç	Y'De Y'	A A A A A A A A A A A A A A A A A A A
17	IOHR	I	P1[1]	ISSP CLK ^{[27],} I ² C SCL, SPI MOSI			W Co	SPI CL	sci, spi SDA, SP Al, EX
18	Po	wer	V _{SS}	Ground connection					120
19	I/O		D+	USB D+					ATA'
20	I/O		D-	USB D-					SP C
21	Po	wer	V _{DD}	Supply voltage					
22	IOHR	I	P1[0]	ISSP DATA ^[27] , I ² C SDA, SPI CLK ^[28]				[27]	[27, 28]
23	IOHR	I	P1[2]		Pin No.	Digital	Analog	Name	Description
24	IOHR	I	P1[4]	Optional external clock input (EXTCLK)	37	IOH	I	P0[0]	
25	IOHR		P1[6]		38	IOH	I	P0[2]	
26	In	put	XRES	Active high external reset with internal pull-down	39	IOH	Ι	P0[4]	
27	I/O		P3[0]		40	IOH	I	P0[6]	
28	I/O		P3[2]		41	P	ower	V _{DD}	Supply voltage
29	I/O	-	P3[4]		42 ^[26]			OCDO	OCD even data I/O
30	I/O	-	P3[6]		43 ^[26]			OCDE	OCD odd data output
31	I/O	_	P4[0]		44	IOH	I	P0[7]	
32	I/O	I	P4[2]		45	IOH	I	P0[5]	
33	I/O	I	P2[0]		46	IOH	I	P0[3]	
34	I/O	I	P2[2]		47	P	ower	V _{SS}	Ground connection
35	I/O	I	P2[4]		48	IOH	I	P0[1]	
36	I/O	Ι	P2[6]		СР	Р	ower	V _{SS}	Center pad must be connected to ground

Table 7. Pin Definitions – CY8C240093 ^[24, 25]

LEGEND A = Analog, I = Input, O = Output, NC = No Connection H = 5 mA High Output Drive, R = Regulated Output.

Notes

23.36 GPIOs.

24. This part is available in limited quantities for In-Circuit Debugging during prototype development. It is not available in production volumes.

25. The center pad (CP) on the QFN package must be connected to ground (V_{SS}) for best mechanical, thermal, and electrical performance. If not connected to ground, it must be electrically floated and not connected to any other signal.

26. This pin (associated with OCD part only) is required for connecting the device to ICE-Cube In-Circuit Emulator for firmware debugging purpose. To know more about the usage of ICE-Cube, refer to CY3215-DK PSoC[®] IN-CIRCUIT EMULATOR KIT GUIDE.

27. On Power-up, the SDA(P10)] drives a strong high for 256 sleep clock cycles and drives resistive low for the next 256 sleep clock cycles. The SCL(P1[1]) line drives resistive low for 512 sleep clock cycles and both the pins transition to High impedance state. On reset, after XRES de- asserts, the SDA and the SCL lines drive resistive low for 8 sleep clock cycles and transition to high impedance state. In both cases, a pull-up resistance on these lines combines with the pull-down resistance (5.6K ohm) and form a potential divider. Hence, during power-up or reset event, P1[1] and P1[0] may disturb the I2C bus. Use alternate pins if you encounter issues.
 28. Alternate SPI clock.



DC Chip-Level Specifications (CY8C24193/493)

The following table lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 10. DC Chip-Level Specifications

Symbol	Description	Conditions	Min	Тур	Max	Units
V _{DD} ^[29, 43]	Supply voltage	See table DC POR and LVD Specifications (CY8C24093/293/393/693) on page 37	1.71	-	5.50	V
I _{DD24}	Supply current, IMO = 24 MHz	Conditions are V_DD \leq 3.0 V, T_A = 25 °C, CPU = 24 MHz.	-	2.88	4.00	mA
I _{DD12}	Supply current, IMO = 12 MHz	Conditions are V _{DD} \leq 3.0 V, T _A = 25 °C, CPU = 12 MHz.	-	1.71	2.60	mA
I _{DD6}	Supply current, IMO = 6 MHz	Conditions are V _{DD} \leq 3.0 V, T _A = 25 °C, CPU = 6 MHz.	-	1.16	1.80	mA
I _{SB0}	Deep sleep current	$V_{DD}\!\leq\!3.0$ V, T_{A} = 25 °C, I/O regulator turned off	-	0.10	1.1	μΑ
I _{SB1}	Standby current with POR, LVD and sleep timer	$V_{DD}\!\le\!3.0$ V, T_A = 25 °C, I/O regulator turned off	-	1.07	1.50	μA
I _{SBI2C}	Standby current with I ² C enabled	Conditions are V _{DD} = 3.3 V, T _A = 25 °C and CPU = 24 MHz	-	1.64	-	μA

Notes

Notes
29. When V_{DD} remains in the range from 1.71 V to 1.9 V for more than 50 µs, the slew rate when moving from the 1.71 V to 1.9 V range to greater than 2 V must be slower than 1 V/500 µs to avoid triggering POR. The only other restriction on slew rates for any other voltage range or transition is the SR_{POWER_UP} parameter.
30. If powering down in standby sleep mode, to properly detect and recover from a V_{DD} brown out condition any of the following actions must be taken:

a. Bring the device out of sleep before powering down.
b. Assure that V_{DD} falls below 100 mV before powering back up.
c. Set the No Buzz bit in the OSC_CR0 register to keep the voltage monitoring circuit powered during sleep.
d. Increase the buzz rate to assure that the falling edge of V_{DD} is captured. The rate is configured through the PSSDC bits in the SLP_CFG register. For the referenced registers, refer to the Technical Reference Manual. In deep sleep/standby sleep mode, additional low power voltage monitoring circuitry allows V_{DD} brown out conditions to be detected and resets the device when V_{DD} goes lower than 1.1 V at edge rates slower than 1 V/ms.



Table 13. 1.71 V to 2.4 V DC GPIO Specifications

Symbol	Description	Conditions	Min	Тур	Max	Units
R _{PU}	Pull-up resistor	-	4	5.60	8	kΩ
V _{OH1}	High output voltage Port 2 or 3 pins	I_{OH} = 10 μ A, maximum of 10 mA source current in all I/Os	V _{DD} – 0.20	-	-	V
V _{OH2}	High output voltage Port 2 or 3 pins	I _{OH} = 0.5 mA, maximum of 10 mA source current in all I/Os	V _{DD} – 0.50	-	-	V
V _{OH3}	High output voltage Port 0 or 1 pins with LDO regulator Disabled for Port 1	I_{OH} = 100 μ A, maximum of 10 mA source current in all I/Os	V _{DD} – 0.20	-	-	V
V _{OH4}	High output voltage Port 0 or 1 Pins with LDO Regulator Disabled for Port 1	I _{OH} = 2 mA, maximum of 10 mA source current in all I/Os	V _{DD} – 0.50	-	-	V
V _{OL}	Low output voltage	I _{OL} = 5 mA, maximum of 20 mA sink current on even port pins (for example, P0[2] and P1[4]) and 30 mA sink current on odd port pins (for example, P0[3] and P1[5])	_	-	0.40	V
V _{IL}	Input low voltage	-	-	-	$0.30 \times V_{DD}$	V
V _{IH}	Input high voltage	-	$0.65 \times V_{DD}$	-	-	V
V _H	Input hysteresis voltage	-	-	80	-	mV
IIL	Input leakage (absolute value)	-	_	1	1000	nA
C _{PIN}	Capacitive load on pins	Package and pin dependent temp = 25 °C	0.50	1.70	7	pF

Table 14. GPIO Current Sink and Source Specifications

Supply Voltage	Mode	Port 1 per I/O (max)	Port 2/3/4 per I/O (max)	Total Current Even Pins (max)	Total Current Odd Pins (max)	Units
1.71 – 2.4	Sink	5	5	20	0 30	
	Source	2	0.5	10	[31]	mA
2.4 – 3.0	Sink	10	10	30	30	mA
	Source	2	0.2	10	[31]	mA
3.0 – 5.0	Sink	25	25	60	60	mA
	Source	5	1	20	[31]	mA



ADC Electrical Specifications (CY8C24193/493)

Table 18. ADC User Module Electrical Specifications

Symbol	Description	Conditions	Min	Тур	Max	Units
Input	·	•				
V _{IN}	Input voltage range	-	0	-	VREFADC	V
C _{IIN}	Input capacitance	-	-	-	5	pF
R _{IN}	Input resistance	Equivalent switched cap input resistance for 8-, 9-, or 10-bit resolution	1/(500fF × data clock)	1/(400fF × data clock)	1/(300fF × data clock)	Ω
Reference	· ·	•				
V _{REFADC}	ADC reference voltage	_	1.14	-	1.26	V
Conversion Rate	· · · · · · · · · · · · · · · · · · ·	•				
F _{CLK}	Data clock	Source is chip's internal main oscillator. See AC Chip-Level Specifications on page 25 for accuracy	2.25	-	6	MHz
S8	8-bit sample rate	Data clock set to 6 MHz. sample rate = 0.001/ (2^Resolution/Data Clock)	_	23.43	_	ksps
S10	10-bit sample rate	Data clock set to 6 MHz. sample rate = 0.001/ (2^resolution/data clock)	_	5.85	_	ksps
DC Accuracy	•				•	
RES	Resolution	Can be set to 8, 9, or 10 bit	8	-	10	bits
DNL	Differential nonlinearity	-	-1	-	+2	LSB
INL	Integral nonlinearity	-	-2	-	+2	LSB
E _{OFFSET}	Offset error	8-bit resolution	0	3.20	19.20	LSB
		10-bit resolution	0	12.80	76.80	LSB
E _{GAIN}	Gain error	For any resolution	-5	-	+5	%FSR
Power	· ·	•				
I _{ADC}	Operating current	-	-	2.10	2.60	mA
PSRR	Power supply rejection ratio	PSRR (V _{DD} > 3.0 V)	-	24	-	dB
		PSRR (V _{DD} < 3.0 V)	_	30	_	dB



Electrical Specifications (CY8C24093/293/393/693)

This section presents the DC and AC electrical specifications of the CY8C24093/293/393/693 PSoC devices. For the latest electrical specifications, confirm that you have the most recent datasheet by visiting the web at http://www.cypress.com/psoc.



Figure 16. Voltage versus CPU Frequency

Absolute Maximum Ratings (CY8C24093/293/393/693)

Exceeding maximum ratings may shorten the useful life of the device. User guidelines are not tested.

Table 33. Absolute Maximum Ratings

Symbol	Description	Conditions	Min	Тур	Мах	Units
T _{STG}	Storage temperature	Higher storage temperatures reduce data retention time. Recommended Storage Temperature is $+25$ °C ± 25 °C. Extended duration storage temperatures above 85 °C degrades reliability.	-55	+25	+125	°C
V _{DD}	Supply voltage relative to V_{SS}	-	-0.5	_	+6.0	V
V _{IO}	DC input voltage	-	$V_{SS} - 0.5$	-	V _{DD} + 0.5	V
V _{IOZ} ^[42]	DC voltage applied to tristate	-	$V_{SS} - 0.5$	-	V _{DD} + 0.5	V
I _{MIO}	Maximum current into any port pin	-	-25	-	+50	mA
ESD	Electrostatic discharge voltage	Human body model ESD	2000	-	_	V
LU	Latch-up current	In accordance with JESD78 standard	_	-	200	mA

Operating Temperature (CY8C24093/293/393/693)

Table 34. Operating Temperature

Symbol	Description	Conditions	Min	Тур	Max	Units
T _A	Ambient temperature	-	-40	-	+85	°C
Т _С	Commercial temperature range	-	0		70	°C
TJ	Operational die temperature	The temperature rise from ambient to junction is package specific. Refer the Thermal Impedances on page 49. The user must limit the power consumption to comply with this requirement.	-40	_	+100	°C

Note

42. Port1 pins are hot-swap capable with I/O configured in High-Z mode, and pin input voltage above V_{DD}.



Table 38. 1.71 V to 2.4 V DC GPIO Specifications (continued)

Symbol	Description	Conditions	Min Typ		Max	Units
V _{IL}	Input low voltage	-	-	_	$0.30 \times V_{DD}$	V
V _{IH}	Input high voltage	-	$0.65 \times V_{DD}$	_	_	V
V _H	Input hysteresis voltage	-	-	80	-	mV
IIL	Input leakage (absolute value)	-	-	1	1000	nA
C _{PIN}	Capacitive load on pins	Package and pin dependent temp = 25 °C	0.50	1.70	7	pF

Table 39. DC Characteristics – USB Interface

Symbol	Description	Conditions	Min	Тур	Max	Units
R _{USBI}	USB D+ pull-up resistance	With idle bus	900	-	1575	Ω
R _{USBA}	USB D+ pull-up resistance	While receiving traffic	1425	-	3090	Ω
V _{OHUSB}	Static output high	-	2.8	-	3.6	V
V _{OLUSB}	Static output low	-	_	-	0.3	V
V _{DI}	Differential input sensitivity	-	0.2	-		V
V _{CM}	Differential input common mode range	-	0.8	-	2.5	V
V _{SE}	Single ended receiver threshold	-	0.8	-	2.0	V
C _{IN}	Transceiver capacitance	-	-	-	50	pF
I _{IO}	High Z state data line leakage	On D+ or D- line	-10	-	+10	μΑ
R _{PS2}	PS/2 pull-up resistance	-	3000	5000	7000	Ω
R _{EXT}	External USB series resistor	In series with each USB pin	21.78	22.0	22.22	Ω

DC Analog Mux Bus Specifications (CY8C24093/293/393/693)

The following table lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 40. DC Analog Mux Bus Specifications

Symbol	Description	Conditions	Min	Тур	Max	Units
R _{SW}	Switch resistance to common analog bus	-	_	-	800	Ω
R _{GND}	Resistance of initialization switch to V_{SS}	_	-	_	800	Ω

The maximum pin voltage for measuring R_{SW} and R_{GND} is 1.8 V

DC Low Power Comparator Specifications (CY8C24093/293/393/693)

The following table lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 41. DC Comparator Specifications

Symbol	Description	Conditions	Min	Тур	Max	Units
V _{LPC}	Low power comparator (LPC) common mode	Maximum voltage limited to V _{DD}	0.0	_	1.8	V
I _{LPC}	LPC supply current	-	-	10	40	μA
V _{OSLPC}	LPC voltage offset	-	-	3	30	mV



DC I²C Specifications (CY8C24093/293/393/693)

The following tables list guaranteed maximum and minimum specifications for the voltage and temperature ranges: 3.0 V to 5.5 V and –40 °C \leq T_A \leq 85 °C, 2.4 V to 3.0 V and –40 °C \leq T_A \leq 85 °C, or 1.71 V to 2.4 V and –40 °C \leq T_A \leq 85 °C, respectively. Typical parameters apply to 5 V and 3.3 V at 25 °C and are for design guidance only.

Table 46. DC I²C Specifications

Symbol	Description	Conditions	Min	Тур	Max	Units
V _{ILI2C}	Input low level	3.1 V ≤ V _{DD} ≤ 5.5 V	-	-	0.25 × V _{DD}	V
		$2.5 \text{ V} \le \text{V}_{\text{DD}} \le 3.0 \text{ V}$	-	-	0.3 × V _{DD}	V
		$1.71 \text{ V} \le \text{V}_{\text{DD}} \le 2.4 \text{ V}$	-	_	0.3 × V _{DD}	V
V _{IHI2C}	Input high level	$1.71 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}$	$0.65 \times V_{DD}$	_	-	V

DC Reference Buffer Specifications (CY8C24093/293/393/693)

The following tables list guaranteed maximum and minimum specifications for the voltage and temperature ranges: 3.0 V to 5.5 V and -40 °C \leq T_A \leq 85 °C, 2.4 V to 3.0 V and -40 °C \leq T_A \leq 85 °C, or 1.71 V to 2.4 V and -40 °C \leq T_A \leq 85 °C, respectively. Typical parameters apply to 5 V and 3.3 V at 25 °C and are for design guidance only.

Table 47. DC Reference Buffer Specifications

Symbol	Description	Conditions	Min	Тур	Max	Units
V _{Ref}	Reference buffer output	1.7 V ≤ V _{DD} ≤ 5.5 V	1	-	1.05	V
V _{RefHi}	Reference buffer output	$1.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	1.2	-	1.25	V

DC IDAC Specifications (CY8C24093/293/393/693)

The following table lists guaranteed maximum and minimum specifications for the entire voltage and temperature ranges.

Table 48. DC IDAC Specifications

Symbol	Description	Min	Тур	Max	Units	Notes
IDAC_DNL	Differential nonlinearity	-4.5	-	+4.5	LSB	
IDAC_INL	Integral nonlinearity	-5	-	+5	LSB	
IDAC_Gain	Range = 0.5x	6.64	-	22.46	μA	DAC setting = 128 dec
(Source)	Range = 1x	14.5	-	47.8	μA	
	Range = 2x	42.7	-	92.3	μA	
	Range = 4x	91.1	-	170	μA	DAC setting = 128 dec
	Range = 8x	184.5	_	426.9	μA	DAC setting = 128 dec



Table 58. SPI Slave AC Specifications

Symbol	Description	Conditions	Min	Тур	Max	Units
F _{SCLK}	SCLK clock frequency	-	-	-	4	MHz
t _{LOW}	SCLK low time	-	42	-	-	ns
t _{HIGH}	SCLK high time	-	42	-	-	ns
t _{SETUP}	MOSI to SCLK setup time	-	30	-	-	ns
t _{HOLD}	SCLK to MOSI hold time	-	50	-	-	ns
t _{ss_miso}	SS high to MISO valid	-	-	-	153	ns
t _{SCLK_MISO}	SCLK to MISO valid	-	-	-	125	ns
t _{SS_HIGH}	SS high time	-	50	-	-	ns
t _{SS_CLK}	Time from SS low to first SCLK	-	2/SCLK	-	-	ns
t _{CLK_SS}	Time from last SCLK to SS high	-	2/SCLK	-	-	ns











Figure 25. 16-pin Chip On Lead (3 × 3 × 0.6 mm) LG16A/LD16A (Sawn) Package Outline, 001-09116



NOTES

1. REFERENCE JEDEC # MO-220

2. ALL DIMENSIONS ARE IN MILLIMETERS

001-09116 *J

TOP VIEW SIDE VIEW BOTTOM VIEW - 6.00±0.10 -PIN# 1 ID 37 37 48 48 0 36 0.40±0.05 C PIN 1 DOT 6.00±0.10 4.60±0.10 0.20±0.05 12 25 12 hononononon 24 13 0.05 MAX 13 - 0.60 MAX ---- 0.40±0.10 4.60±0.10 0.08 NOTES: 1. HATCH AREA IS SOLDERABLE EXPOSED PAD 2. REFERENCE JEDEC # MO-248 3. PACKAGE WEIGHT: 68 ±7 mg 001-57280 *E 4. ALL DIMENSIONS ARE IN MILLIMETERS

Figure 26. 48-pin QFN (6 × 6 × 0.6 mm) LQ48A 4.6 × 4.6 E-Pad (Sawn) Package Outline, 001-57280





Figure 27. 48-pin QFN (7 × 7 × 1.0 mm) LT48A 5.1 × 5.1 E-Pad (SAWN) Package Outline, 001-13191

Important Notes

- For information on the preferred dimensions for mounting QFN packages, see the following Application Note at http://www.amkor.com/products/notes_papers/MLFAppNote.pdf.
- Pinned vias for thermal conduction are not required for the low power PSoC device.



Development Tool Selection

Software

PSoC Designer™

At the core of the PSoC development software suite is PSoC Designer. Utilized by thousands of PSoC developers, this robust software has been facilitating PSoC designs for over half a decade. PSoC Designer is available free of charge at http://www.cypress.com.

PSoC Programmer

Flexible enough to be used on the bench in development, yet suitable for factory programming, PSoC Programmer works either as a standalone programming application or it can operate directly from PSoC Designer. PSoC Programmer software is compatible with both PSoC ICE-Cube In-Circuit Emulator and PSoC MiniProg. PSoC Programmer is available free of charge at http://www.cypress.com.

Development Kits

All development kits are sold at the Cypress Online Store.

CY3215-DK Basic Development Kit

The CY3215-DK is for prototyping and development with PSoC Designer. This kit supports in-circuit emulation and the software interface enables users to run, halt, and single step the processor and view the content of specific memory locations.

PSoC Designer supports the advance emulation features also. The kit includes:

- PSoC Designer Software CD
- ICE-Cube In-Circuit Emulator
- ICE Flex-Pod for CY8C29X66A Family
- Cat-5 Adapter
- Mini-Eval Programming Board
- 110 ~ 240 V Power Supply, Euro-Plug Adapter
- iMAGEcraft C Compiler (Registration Required)
- ISSP Cable
- USB 2.0 Cable and Blue Cat-5 Cable
- 2 CY8C29466A-24PXI 28-PDIP Chip Samples

Evaluation Tools

All evaluation tools are sold at the Cypress Online Store. For more information on PSoC 1 kits, visit the link http://www.cypress.com/?rID=63754

Device Programmers

All device programmers are purchased from the Cypress Online Store.



Document Conventions

Units of Measure

Table 64. Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
dB	decibel
fF	femtofarad
g	gram
Hz	hertz
KB	1024 bytes
Kbit	1024 bits
KHz	kilohertz
Ksps	kilo samples per second
kΩ	kilohm
MHz	megahertz
MΩ	megaohm
μA	microampere
μF	microfarad
μH	microhenry
μS	microsecond
μW	microwatt
mA	milliampere
ms	millisecond
mV	millivolt
nA	nanoampere
nF	nanofarad
ns	nanosecond
nV	nanovolt
W	ohm
pА	picoampere
pF	picofarad
рр	peak-to-peak
ppm	parts per million
ps	picosecond
sps	samples per second
s	sigma: one standard deviation
V	volt
W	watt

Reference Documents

- Technical reference manual for CY8C24x93 devices
- In-system Serial Programming (ISSP) protocol for CY8C24x93 (AN2026C)
- Host Sourced Serial Programming for CY8C24x93 devices (AN59389)

Numeric Naming

Hexadecimal numbers are represented with all letters in uppercase with an appended lowercase 'h' (for example, '14h' or '3Ah'). Hexadecimal numbers may also be represented by a '0x' prefix, the C coding convention. Binary numbers have an appended lowercase 'b' (for example, 01010100b' or '01000011b'). Numbers not indicated by an 'h', 'b', or 0x are decimal.





5. Wake-up from Sleep with Hardware I2C Address match on Pins P1[0], P1[1]

Problem Definition

I2C interface needs 20 ns hold time on SDA line with respect to falling edge of SCL, to wake-up from sleep using I2C hardware address match event.

Parameters Affected

t_{HD;DAT} increased to 20 ns from 0 ns

■ Trigger Condition(S)

This is an issue only when all these three conditions are met:

1) P1.0 and P1.1 are used as I2C pins,

2) Wakeup from sleep with hardware address match feature is enabled, and

3) I2C master does not provide 20 ns hold time on SDA with respect to falling edge of SCL.

■ Scope of Impact

These trigger conditions cause the device to never wake-up from sleep based on I2C address match event

Workaround

For a design that meets all of the trigger conditions, the following suggested circuit has to be implemented as a work-around. The R and C values proposed are 100 ohm and 200 pF respectively.



Fix Status

Will not be fixed

Changes

None



Appendix B: Silicon Errata for the PSoC[®] CY8C24193/493 Families

This section describes the errata for the PSoC[®] CY8C24193/493 families. Details include errata trigger conditions, scope of impact, available workarounds, and silicon revision applicability.

Contact your local Cypress Sales Representative if you have questions.

CY8C24193/493 Qualification Status

Product Status: Production released.

CY8C24193/493 Errata Summary

The following Errata items apply to the CY8C24193/493 datasheet 001-86894.

1. Wakeup from sleep may intermittently fail

Problem Definition

When the device is put to sleep in Standby or I2C_USB Mode and the bandgap circuit is refreshed less frequently than every 8 ms (default), the device may not come out of sleep when a sleep-ending input is received.

Parameters Affected

None

Trigger Condition(S)

By default, when the device is in the Standby or I2C_USB sleep modes, the bandgap circuit is powered-up approximately every 8 ms to facilitate detection of POR or LVD events. This interval can be lengthened or the periodic power-up disabled to reduce sleep current by setting the ALT_BUZZ bits in the SLP_CFG2 register or the Disable Buzz bit in the OSC_CR0 register respectively. If the bandgap circuit refresh interval is set longer than the default 8 ms, the device may fail to wakeup from sleep and enter a locked up state that can only be recovered by Watchdog Reset, XRES, or POR.

Scope of Impact

The trigger conditions outlined above may cause the device to never wakeup.

Workaround

Prior to entering Standby or I2C_USB sleep modes, do not lengthen or disable the bandgap refresh interval by manipulating the ALT_BUZZ bits in the SLP_CFG2 register or the Disable Buzz bit in the OSC_CR0 register respectively.

Fix Status

This issue will not be corrected in the next silicon revision.



2. I²C Errors

Problem Definition

The I^2C block exhibits occasional data and bus corruption errors when the I^2C master initiates transactions while the device is transitioning in to or out of sleep mode.

Parameters Affected

Affects reliability of I²C communication to device, and between I²C master and third party I²C slaves.

■ Trigger Condition(S)

Triggered by transitions into and out of the device's sleep mode.

Scope of Impact

Data errors result in incorrect data reported to the I^2C master, or incorrect data received from the master by the device. Bus corruption errors can corrupt data in transactions between the I^2C master and third party I^2C slaves.

Workaround

Firmware workarounds are available in firmware. Generally the workaround consists of disconnecting the I^2C block from the bus prior to going to sleep modes. I^2C transactions during sleep are supported by a protocol in which the master wakes the device prior to the I^2C transaction.

Fix Status

To be fixed in future silicon.

Changes

None

3. DoubleTimer0 ISR

Problem Definition

When programmable timer 0 is used in "one-shot" mode by setting bit 1 of register 0,B0h (PT0_CFG), and the timer interrupt is used to wake the device from sleep, the interrupt service routine (ISR) may be executed twice.

Parameters Affected

No datasheet parameters are affected.

Trigger Condition(S)

Triggered by enabling one-shot mode in the timer, and using the timer to wake from sleep mode.

Scope of Impact

The ISR may be executed twice.

Workaround

In the ISR, firmware should clear the one-shot bit with a statement such as "and reg[B0h], FDh"

Fix Status

Will not be fixed

Changes

None



6. Wakeup from sleep with analog interrupt

Problem Definition

Device wakes up from sleep when an analog interrupt is trigger

Parameters Affected

No datasheet parameters are affected.

■ Trigger Condition(S)

Triggered by enabling analog interrupt during sleep mode when device operating temperature is 50 °C or above

Scope of Impact

Device unexpectedly wakes up from sleep

Workaround

Disable the analog interrupt before entering sleep and turn it back on upon wakeup.

Fix Status

Will not be fixed

Changes

None